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RANDOM ACCESS MEMORY USING PRECHARGE TIMERS IN TEST MODE

Abstract

Embodiments of the present invention are illustrated in a random access memory. In one embodiment, the random access memory comprises memory banks and precharge timers configured to provide precharge signals to the memory banks. Each of the precharge timers corresponds to one of the memory banks and each of the precharge timers is configured to provide one of the precharge signals to the corresponding one of the memory banks in normal mode and in test mode.